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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. MI22-2379

APPLICANT

July 31, 2003

SERIAL NO. 10/632,273

IST OF ART CITED BY APPLICANT (Use several sheets if necessary)

Warren M. Farnworth
FILING DATE

GROUP 2829

U.S. PATENT DOCUMENTS

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